# ECE 4150/6250 - Synopsys Tutorial: Using DFT Compiler & TetraMax

# Objectives:

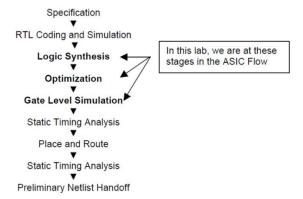
- Use Synopsys Design Compiler's DFT, synthesize 'scan-cell' test structures into verilog code
- Use Synopsys TetraMax tool, to generate test patterns (ATPG) for the 'test structures' from the Design Compiler's output
- Use Verilog to test the output of the TetraMax tool's patterns against the synthesized code

#### Assumptions:

- Student has completed lab 4
- Student a basic understanding of scan-chain theory.

#### Introduction:

The ASIC design flow is as follows:



In lab 3 we introduced the Synopsys Logic Synthesis tool called the Design Compiler. In this lab we will use the

Design Compiler to insert test structures into our synthesized verilog code. We will then use the Synopsys TetraMAX® tool to exercise these test structures with a pattern of 1's and 0's. Prior to using these tools, you should be familiar with the basics of common testing methodologies used throughout the industry.

1)

# **Overview of this Design For Test Tutorial:**

We will use Synopsys Design Vision to automatically insert multiplexed flip/flops into our synthesized design and to interconnect them into scan-chains. Then we will use TetraMax to generate the patterns that will test the scan-chains in our design. Finally we will export the patterns to a verilog test bench and use it to test the scanchains inserted into our synthesized design.

## Part I: File Setup for This Lab

Any time you wish to "synthesize" some verilog code, create a directory in your ece4150\_6250 folder to house all of the files that will be created during the synthesis process.

Note: You can change the suggested "ece4150\_6250" folder name to your own one in the labs thereafter.

1. Login to a workstation, open up a terminal window and type:

```
Cd ece4150_6250

mkdir
lab5
cd
lab5

mkdir
reports
mkdir
work
mkdir
src
mkdir
db
```

Always create the "reports" "work" "src" and "db" directories in whatever directory you decide to work under.

Copy the AMI 0.5 "standard cell library's verilog code into your "src" directory: cp

```
/apps/design_kits/osu_stdcells_v2p7/cadence/lib/ami05/lib/osu05_stdcells.v ~/ece4150_6250/lab5/src
```

Copy the OSU scan cell library's verilog code into your "src" directory: cp

```
/home/seas/vlsi/course ece128/lab files/lab5/src/osu scan.v ~/ece4150 6250/lab5/src
```

Copy the OSU scan cell library's Synopsys database into you "db" directory:

```
cp /home/seas/vlsi/course ece128/lab files/lab5/db/osu scan.db ~/ece4150 6250/lab5/db
```

- 2. Copy the verilog code you wish to synthesize into the "src" subdirectory:
  - In this lab, we want to use a modified ripplecarry adder from the ATPG tutorial:
  - We will use a 'master' copy of this code, so that the instructions and names for modules in this
    lab match up. So you will copy the 'fulladder' from the VLSI account, instead of using your own
    for this lab.

```
cp /home/seas/vlsi/course_ece128/lab_files/lab5/src/fulladder.v
    ~/ece4150_6250/lab5/src

cp /home/seas/vlsi/course_ece128/lab_files/lab5/src/halfadder.v
    ~/ece4150_6250/lab5/src

cp /home/seas/vlsi/course_ece128/lab_files/lab5/src/fulladder_tb.v
    ~/ece4150_6250/lab5/src
```

• The above three lines copy the "fulladder" "halfadder" and the test bench we created in lab1 into 'src' directory underneath the lab4 directory you created in step1.

```
cp /home/seas/vlsi/course_ece128/lab_files/lab5/src/ripplecarry4_clk.v
~/ece4150 6250/lab5/src
```

- This ripplecarry adder is 4-bits. It uses 4 fulladder's chained together. The only difference is that in between the fulladders, there is a clocked d-flip/flop. While this has no practical application, it is a quick example of a circuit with 'sequential' logic, which we need for this tutorial.
  - This ripplecarry adder is different from the rippler carry adder used in the ATPG tutorial.
     It has an active high reset added to it. This design flow will not work with designs that have asynchronous sets or resets.
- 3. Copy synthesis scripts into your lab 4 directory:

```
cp /home/seas/vlsi/course_ece128/lab_files/lab5/dc_syn.tcl
~/ece4150_6250/lab5

cp /home/seas/vlsi/course_ece128/lab_files/lab5/dc_test.tcl
~/ece4150_6250/lab5

cp /home/seas/vlsi/course_ece128/lab_files/lab5/tmax_atpg.tcl
~/ece4150_6250/lab5
```

# Part II Synthesizing the Ripple Counter (with registers) using Synopsys Design Vision:

1. Change to your working directory

```
cd ~/ece4150 6250/lab5
```

- 2. Start the design compiler's GUI by typing design\_vision (note: do NOT put an "&" after this command, it needs to run in the foreground)
- 3. Run the design compiler script to synthesize your code automatically into AMI .5 technology:

From the menu, choose: File->Execute Script

Browse for the file named: dc\_syn.tcl (it should be in the lab5 directory)

What this script does is all of the things we did in lab3 automatically:

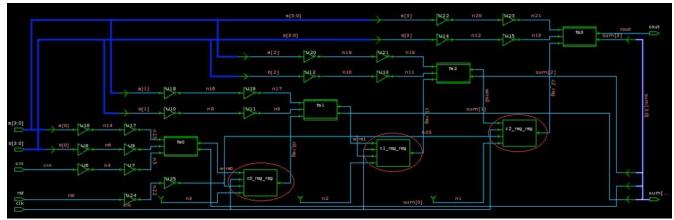
- It analyzes and elaborates your verilog code
- It sets up a 'reference clock of 25MHz' and sets up constraints on the input and output pins
- It then compiles the design with the *constraints* and synthesizes your design using AMI .5 gates
- It saves the synthesized design in verilog code format
- It writes out reports discussing the progress of the synthesis

Design Compiler can also be run via the command line. To execute the script via the command line, execute the following command from ~/ece4150\_6250/lab5

```
dc shell-t -f dc syn.tcl
```

To start Design Vision and have it automatically load the script, execute the following command from ~/ece4150\_6250/lab5

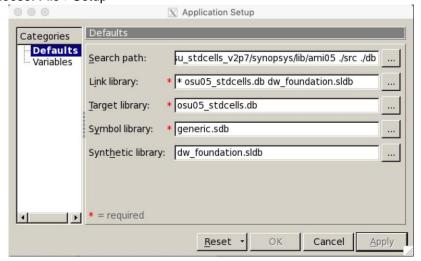
- 4. Check the error log, ensure that no errors are present before continuing
- 5. Open up the schematic window, the 4-bit ripple carry adder should be synthesized using AMI .5 standard gates. Verify that there is a DFF in between each fulladder circuit. **Do not exist Design Vision.**



- 6. To show that you've completed this section of the lab, fill in the answers below regarding the ripplecarry adder, post the questions along with your answers to the BB before next lab:
  - How many inputs combinations are possible for our ripplecarry adder?
  - How many internal states can our ripplecarry adder have?
  - What was the total dynamic power estimated for the ripplecarry adder?

# PART III Inserting the Test Structures:

- 1. Check your setup:
  - From the menu, choose: File->Setup



```
Search Path:
```

```
/apps/vlsi_2018/synopsys/synthesis/O-2018.06-SP1/libraries/syn/apps/vlsi_2018/synopsys/synthesis/O-2018.06-SP1/minpower/syn/apps/vlsi_2018/synopsys/synthesis/O-2018.06-SP1/dw/syn_ver/apps/vlsi_2018/synopsys/synthesis/O-2018.06-SP1/dw/sim_ver/apps/vlsi_2018/synopsys/synthesis/O-2018.06/libraries/syn/gtech.db/home/class/vlsi/course_all/UofU/UofU_Digital_v1_2_oa3/apps/design_kits/osu_stdcells_v2p7/synopsys/lib/ami05 ./src
```

#### Link library:

\* osu05 stdcells.db dw foundation.sldb

# Target library:

osu05 stdcells.db

# Symbol library:

generic.sdb

# Synthetic library:

dw foundation.sldb

Copy & Paste the following commands into the Design\_Vision Prompt in order to setup variables for scan chain insertion:

```
# Setup variables for testing
files set scan_library [list osu_scan.db] ; # Library with
scan chain cells set scancell DFFPOSX1 SCAN ; # Name of
ScanFF Cell
# Setup timing variables for dft drc command
set test default delay 0 ; # define time when values are applied to input
      ports
set test default bidir delay 0 ; # Defines the default switching time of
      bidirectional
                                # ports in a tester cycle.
set test default strobe 40 ; # default strobe time in a test cycle for output
ports
                              # and bidirectional ports in output mode
set test default period 100 ; # Defines the default length of a test vector
cycle
# Setup scan chain for insert dft
set test default scan style multiplexed flip flop;
# Defines the default scan style for the insert dft command.
# type "man test default scan style" for more information

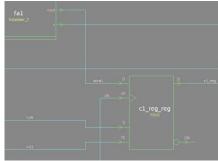
    The commands above setup some timing information for the design for test (DFT)
```

3. Copy & Paste the following commands into the Design\_Vision Prompt in order to insert test structures into your design:

```
# Update filebase
set filebase [format "%s%s" [format "%s%s" $basename "_"] $dft_runname]
# Update target library
set target_library [list $target_library $scan_library]
```

```
# Set the scan cells to use in the
design #set_scan_register_type -type
{DFFPOSX1_SCAN} ;
set_scan_register_type -type
${scancell} ;
# Make sure to add a test_out port
set_scan_configuration -create_dedicated_scan_out_ports true
# Infer clock and reset lines
create_test_protocol -infer_async -
infer_clock dft_drc -verbose
# Replace flip flops with multiplexed
flipflops compile -scan
# Check for constraint violations
report_constraint -all_violators
```

- If the 'design violation browser' appears, simply close that window.
- The 'compile -scan' command replaced all the DFF's in your ripple-carry adder with Multiplexed DFF's.
- Open up the schematic window and see what has happened to all of your DFFs, notice the extra ports on all the DFFs:



- 4. Copy & Paste the following commands into the Design\_Vision Prompt in order to Build a Scan Chains
  - At this point, we have all of the scan-cells inserted into our design, but they are not wired together
    into a scan-chain. You can see that the "TE" or 'test-enable' pin and 'TI" or 'test-input' pins are
    grounded. Use the following commands to build the scan chain.

```
# connects all scan-enabled ff's together into scan-
chain
# note, it creates two new ports: test_si & test_se
insert_dft
# set drive strength of the test ports to 2 (so it isn't assumed to be
infinite) set_drive 2 test_si
set_drive 2 test_se
# since you've already inserted scan-ff's, we don't want that to happen again,
# when we run insert_dft
set_scan_configuration -replace false
# run insert_scan again to set drive-strength constraints
insert_dft
# report any constraints that may have been violated by inserting the test
# structures
report_constraint -all_violators
```

```
dft_drc -verbose -coverage_estimate
report_scan_path -view existing -
chain all report cell
```

5. Copy & Paste the following commands into Design Vision Prompt in order to save reports, test protocol and DFT verilog design

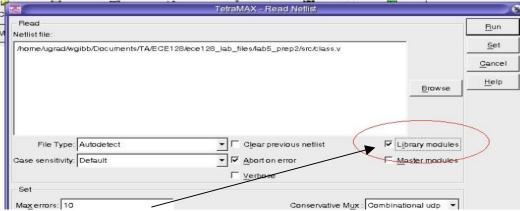
```
# report dft drc
set filename [format "%s%s%s" ./reports/ $filebase
".violators"] redirect $filename { report constraint -
all violators }
# report dft drc
set filename [format "%s%s%s" ./reports/ $filebase
".dft drc"] redirect $filename { dft drc -verbose -
coverage estimate }
# report scan path
set filename [format "%s%s%s" ./reports/ $filebase
".scan path"] redirect $filename { report scan path -view
existing -chain all }
# report cells
set filename [format "%s%s%s" ./reports/ $filebase ".cell"]
redirect $filename { report cell }
# Write out protocol
set filename [format "%s%s%s" ./src/ $filebase
".spf"] write test protocol -output $filename
# Write out scan chain design
set filename [format "%s%s%s" ./src/ $filebase ".v"]
redirect change names { change names -rules verilog -hierarchy -
verbose } write -format verilog -hierarchy -output $filename
```

- close the violation browser
- check for errors, if none, close Design Vision
- 6. Inspect the reports
  - In the 'reports' directory, four new reports: ripplecarry4\_clk\_scan.violators, ripplecarry4\_clk\_scan.dft\_drc, ripplecarry4\_clk\_scan.scan\_path, and ripplecarry4\_clk\_scan.cell have been created. Check them to see if any errors have occurred.
  - A new file, ripplecarry4\_clk\_scan.spf in the src directory has been created. This is a scan chain test protocol file, generated by DFT Compiler. We will use this with Tetramax.
  - A new verilog file has been created in the "src" directory, called: "ripplecarry4 clk scan.v"
  - It contains our ripple\_carry\_adder synthesized into Generic gates, but with a scan-chain inserted into it
  - We will now use this synthesized code in TetraMax to generate patterns for it
- 7. To show that you've completed this section of the lab, fill in the answers below regarding the ripplecarry adder, post the questions along with your answers to the BB before next lab:
  - What command is used to replace your DFF's with Scan-enabled DFF's?
  - What command is used to connected your scan-DFF's into a scan chain?
  - What different types of DFT strategies can DFT\_Compiler insert? What are the differences between them? Hint: Look at the DC\_Test.tcl script as a starting point for information.

Vhat is tl	he estimate	d test cove	erage for t	his design?	?		
	simulate th					Why or wh	y not?
						 	, not:

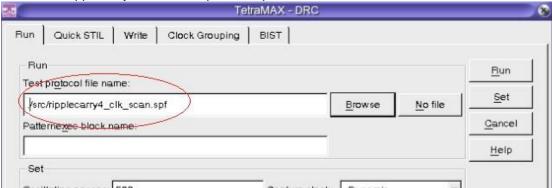
# Creating Test Patterns for the Ripple Carry Adder using Synopsys TetraMAX:

- 1. Change to your working directory: cd ~/ece4150\_6250/lab5
- 2. Start the Synopsys TetraMAX GUI by typing: "tmax &
- 3. Load the OSU standard cell library & Scan Cell library
  - Click on the "NETLIST" button at the top of the screen
  - Browse for file: osu05\_stdcells.v and osu\_scan.v (in your src directory). The osu\_scan.v contains the muxed-FF's Verilog models.



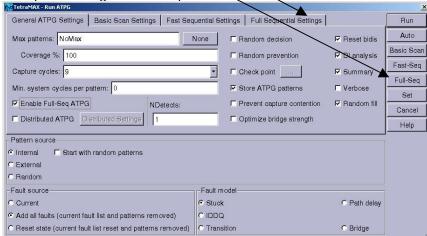
- Click on the "Library Modules" check box, to indicate that these are libraries
- Click on RUN
- 4. Load your Synthesized full adder:
  - Again click on the "NETLIST" button at the top of the screen
  - Browse for the file: ripplecarry4\_clk\_scan.v (in your src directory)
  - UNCHECK the "Library modules" check box, as this is not a library file, it is your design
  - Click on RUN

- 5. **BUILD** the Ripple Carry Adder
  - Click on the "BUILD" button at the top of the screen, accept defaults, and click run
- DRC the Full Adder:
  - Click on the "DRC" button at the top of the screen
  - You'll need to add the Test Protocol file here. Under "Test protocol file name" enter: ./src/ripplecarry4\_clk\_scan.spf. Accept other defaults, and click run



Generate the Test Patterns for the Full Adder:

- Click on the "ATPG" button at the top of the screen (stands for 'automatic test pattern generation')
- · Check the 'add all faults' check box at the bottom of the window
- · Ensure the 'stuck' at fault model is checked
- Click on "Enable Full Seq ATPG"
- . Change the capture cycles to 9
  - . Next, click on the Full Sequential Settings Tab
    - Set the merge effort = low
- Click on "Full-Sequential" to generate the patterns



- Read the generated report & notice the # of faults possible, % of coverage:
- 7. View the patterns TetraMax has generated (with the ATPG sequential scan algorithm)
  - Use the same technique as you did in the last tutorial to show the faults
- Schematic View

- 8. View the results of a possible stuck-at-fault:
- 9. Write out the test patterns to a verilog file

• In TetraMAX type these commands:

```
write_patterns ripplecarry4_clk.stil -format stil -replace
write_testbench -input ripplecarry4_clk.stil -output maxtb -
replace
```

- In terminal type: stil2verilog -generate config myconfig
- Edit the file: myconfig and find the line starts with set cfg\_dut.. and rename it as ripplecarry4\_clk

```
set cfg dut module name " ripplecarry4 clk"
```

- 10. Viewing the Patterns in Simvision
  - Move maxtb.v to src folder: mv maxtb.v ./src
  - Open up an editor (like gedit) and edit the file:

```
gedit ~/ece4150 6250/lab5/src/maxtb.v
```

• Right before the "end module" statement, add the following lines of verilog:

```
Initial begin
$shm_open ("ripplecarry4_clk_scan_patterns.db");
$shm_probe("AS"
); end
```

- 11. Test the patterns out against your Synthesized full adder
  - Close TetraMax
  - Now, on a local workstation type:

```
cd ~/ece4150_6250/lab5/src
```

sim-nc maxtb.v ripplecarry4 clk scan.v osu scan.v osu05 stdcells.v

- 12. To show that you've completed this section of the lab, fill in the answers below regarding the ripple carry adder, post the questions along with your answers to the BB before next lab:
  - How many inputs combinations are possible for a ripple carry adder?
  - How many input combinations did TetraMAX create?
  - What % coverage did TetraMax obtain with the generated patterns?
  - Was this coverage the same coverage DFT Compiler estimated?

You can now use the <a href="dc\_scan.tcl">dc\_scan.tcl</a> script to automatically generate scan chain inserted designs. Like the dc\_syn.tcl script, it does require parameters to be set prior to using it. Likewise, <a href="tmax\_atpg.tcl">tmax\_atpg.tcl</a> can be used to automatically generate ATPG vectors and testbenches for a design. The tmax\_atpg.tcl script will also write out reports to your /reports directory, for your reference.

## Appendix:

For students viewing this tutorial who do not have access to our server, this is a listing of the contents of the files reference in Part II of this tutorial:

- dc\_syn.tcl Synthesis script for Design Compiler. Omitted from this tutorial. See ATPG tutorial for dc syn.tcl.
- dc\_test.tcl Synthesis script for DFT Compiler. Goes through the regular synthesis process and then performs DFT Scan-chain insertation.
  - Note the additional section in the settings, DFT Switches. These are the commands used to drive DFT Compiler.
- Tmax\_atpg.tcl TCL script to drive Tetramax with tutorial commands.
- ripplecarry4\_clk.v Example design used in tutorial.

The Synopsys generic standard cell library can be used in place of the osu\_scan library; however the OSU scan library will be made available from the GWU VLSI site in the future.

## dc test.tcl:

```
\#\#\# Design Compiler Script for ECE 4150/6250
#### Performs Synthesis only to AMI .5 technology
#### note: this is a TCL script
# ITEMS YOU WILL NEED TO SET FOR EACH DESIGN
# 1) myFiles - LIST OF YOUR FILES TO SYNTHESIZE
# 2) basename - TOP LEVEL MODULE IN YOUR
DESIGN # 3) myClk - NAME OF YOUR CLOCK
SIGNAL
# 4) virtual - USE A REAL CLOCK (SEQUENTIAL DESIGNS) OR A VIRTUAL
            CLOCK (COMBINATORIAL DESIGNS)
# 5) myPeriod - SETS THE CLOCK SPEED, THUS DEFINING THE SYNTHESIS SPEED GOAL
# list of all HDL files in the design
set myFiles [list ./src/ripplecarry4 clk.v ./src/fulladder.v ./src/halfadder.v];
set basename ripplecarry4 clk
                          ; # Top-level module name
set myClk clk
               ;# The name of your clock
                ;# 1 if virtual clock, 0 if real clock
set virtual 0
set myPeriod ns 40 ;# desired clock period (in ns) (sets speed goal)
# Some runtime options, change only if needed
set runname syn ;# Name appended to output files set exit dc 0 ;# 1 to exit DC after running, 0 to keep DC running
# set the target library
set target library [list osu05 stdcells.db];
# Control the printing of result files
set verbose 0 ;# 1 Write reports to screen, 0 do not write reports to screen set verbose dft 0 ;# 1 Write reports to screen, 0 do not write reports to screen
# Timing and loading information
set myClkLatency_ns 0.3
set myInDelay ns 2.0
; # clock network latency
set myInDelay ns 2.0
;# delay from clock to inputs valid
set myInDelay ns 2.0
```

```
; # delay from clock to output valid
set myLoadLibrary [file rootname $target library] ;# name of library the cell comes from
            ; # name of pin that the outputs drive
set myLoadPin A
set myMaxFanout
             1
                   ; # max fanout load for input
pins
set myOutputLoad 0.1; # output pin loading
########################## compiler switches...
##################
set optimizeArea 1
                ;# 1 for area, 0 for speed
set useUltra 0
                          ;# 1 for compile ultra, 0 for compile
                           # mapEffort, useUngroup
                           are for # non-ultra
                           compile...
                          ;# 0 if no flatten, 1 if flatten
set useUngroup 0
#####################################
# DFT Switches
set dft runname scan ; # name appended to output
files set scan library [list osu scan.db]; # Library with
scan chain cells set scancell DFFPOSX1 SCAN ; # Name of
ScanFF Cell
# Setup timing variables for dft drc command
set test default delay 0 ; # define time when values are applied to input ports
set test default bidir delay 0 ; # Defines the default switching time of
                         bidirectional # ports in a tester cycle.
set test default strobe 40 ; # default strobe time in a test cycle for output ports
                    # and bidirectional ports in output mode
set test default period 100 ; # Defines the default length of a test vector cycle
# Setup scan chain for insert dft
set test default scan style multiplexed flip flop;
# Defines the default scan style for the insert dft command.
# type "man test default scan style" for more information
# Set some system-level things that RARELY change...
# synthetic library is set in .synopsys dc.setup to be
# the dw foundation library. set link library [concat [concat "*" $target library]
$synthetic library]
;# verilog or VHDL
set fileFormat verilog
### YOU SHOULD NOT NEED TO CHANGE ANYTHING BELOW THIS LINE ###
*************************
#### read in, link to standard cells, and uniquify design ####
# remove any other designs from design compiler's memory
remove design -all
echo IMPORTING DESIGN
```

```
# analyzer & elaborate verilog source
files
######################################
analyze -format $fileFormat -lib WORK
$myFiles elaborate $basename -lib
WORK -update
# set design to 'highest' module level
#####################################
current design $basename
######################################
# link to standard cell libraries and uniquify
#############################
#######
link
uniquify
#### setup clock & all input/output constraints
#### echo SETTING CONSTRAINTS
######################################
# now you can create clocks for the design
# and set other constraints
##############################
###### if { $virtual == 0 } {
  create clock -period $myPeriod ns $myClk
} else {
  create clock -period $myPeriod ns -name $myClk
set_clock_latency $myClkLatency ns
#####################################
# set delays on all inputs & outputs with respect to the clock (in ns)
# set the input and output delay relative to myClk
##############################
###### if { $virtual == 0 } {
   set input delay $myInDelay ns -clock $myClk [all inputs]
} else {
   set_input_delay $myInDelay_ns -clock $myClk [remove_from_collection [all inputs] $myClk]
set output delay $myOutDelay ns -clock $myClk [all outputs]
# Set the driving cell for all inputs except the clock
# The clock has infinite drive by default. This is usually
# what you want for synthesis because you will use
other # tools (like SOC Encounter) to build the
clock tree
# (or define it by hand).
################################
###### if { $virtual == 0 } {
   set driving cell -library $myLoadLibrary -lib cell $myInputBuf [all inputs]
} else {
  set driving cell -library $myLoadLibrary -lib cell $myInputBuf [remove from collection
[all inputs] $myClk]
# set load/fanin/fanout for all inputs/outputs
set load $myOutputLoad [all outputs]
# check value of fanout
```

```
######################################
  set max fanout $myMaxFanout [all inputs]
  set fanout load 8 [all outputs]
  echo DONE SETTING CONSTRAINTS
  # This command will fix the problem of having
  # assign statements left in your structural file.
  # But, it will insert pairs of inverters for feedthroughs!
  set fix multiple port nets -all -buffer constants
  echo BEGIN COMPILING DESIGN
  ######################################
  # optimize for area
  ###############################
  ###### if { $optimizeArea ==
  1} { set_max_area 0
  # now compile the design with given mapping effort # and do a second compile with incremental mapping#
or use the compile ultra meta-command
if { $useUltra == 1 }
  compile_ultra }
else {
  if { $useUngroup == 1 } {
     compile -ungroup all -map effort medium
 } else {
compile -map effort medium -exact_map
 }
} check_design
echo VIOLATIONS
report constraint -all violators
#### generate verilog code for synthesized module ###
#### sdc files, sdf files, design compiler project###
#### and write out reports
OUTPUT FILES AND REPORTS
set filebase [format "%s%s" [format "%s%s" $basename " "] $runname]
######################################
# structural (synthesized) file as verilog
set filename [format "%s%s%s" ./src/ $filebase ".v"]
redirect change_names { change_names -rules verilog -hierarchy -verbose }
write -format verilog -hierarchy -output $filename
# write out the sdf file for back-annotated verilog sim
# This file can be large!
set filename [format "%s%s%s" ./src/ $filebase ".sdf"]
write sdf -version 1.0 $filename
######################################
# this is the timing constraints file generated from the
# conditions above - used in the place and route program
#####################################
set filename [format "%s%s%s" ./src/ $filebase ".sdc"]
write sdc $filename
```

```
#####################################
# generate reports for user to view
if { $verbose == 1 }
{
       report design
       report hierarchy
       report_timing -path full -delay max -nworst 3 -significant_digits 2 -sort_by group
       report timing -path full -delay min -nworst 3 -significant digits 2 -sort by group
       report area
      report_cell
      report_net
       report port -v
       report power -analysis effort low
}
# Design and Hierarchy reports
set filename [format "%s%s%s" ./reports/ $filebase ".design"]
redirect $filename { report design }
set filename [format "%s%s%s" ./reports/ $filebase ".design"]
redirect -append $filename { report hierarchy }
# Timing reports
set filename [format "%s%s%s" ./reports/ $filebase ".timing"]
redirect $filename { report timing -path full -delay max -nworst 5 -significant digits 2 -sort by group
set filename [format "%s%s%s" ./reports/ $filebase ".timing"]
redirect -append $filename { report timing -path full -delay min -nworst 5 -significant digits 2
sort_by group }
# Report cell and report area
set filename [format "%s%s%s" ./reports/ $filebase ".area"]
redirect $filename { report area }
set filename [format "%s%s%s" ./reports/ $filebase ".area"]
redirect -append $filename { report cell }
# Report port
set filename [format "%s%s%s" ./reports/ $filebase ".ports"]
redirect $filename { report port -v}
set filename [format "%s%s%s" ./reports/ $filebase ".net"] redirect
$filename { report net }
# report power
set filename [format "%s%s%s" ./reports/ $filebase ".pow"]
redirect $filename { report_power -analysis_effort low }
#### Insert Test Structures ###
# Update filebase
set filebase [format "%s%s" [format "%s%s" $basename " "] $dft runname]
# Update target library
set target library [list $target library $scan library]
# Set the scan cells to use in the design
#set_scan_register_type -type {DFFPOSX1_SCAN} ;
set scan register type -type ${scancell} ;
# Make sure to add a test out port
set scan configuration -create dedicated scan out ports true
# Infer clock and reset lines
create test protocol -infer async -infer clock
```

```
dft drc -verbose
# Replace flip flops with multiplexed flipflops
compile -scan
# Check for constraint violations
report constraint -all violators
### Building Scan Chains
# connects all scan-enabled ff's together into scan-chain #
note, it creates two new ports: test si & test se
insert dft
# set drive strength of the test ports to 2 (so it isn't assumed to be infinite)
set drive 2 test si
set drive 2 test se
# since you've already inserted scan-ff's, we don't want that to happen again,
# when we run insert dft
set scan configuration -replace false
# run insert scan again to set drive-strength constraints
insert dft
# report any constraints that may have been violated by inserting the test
# structures
if { $verbose dft == 1 } {
report constraint -all violators
                                   dft drc
-verbose -coverage_estimate
report scan path -view existing -chain all report cell
# report dft drc
set filename [format "%s%s%s" ./reports/ $filebase ".violators"]
redirect $filename { report constraint -all violators }
# report dft drc
set filename [format "%s%s%s" ./reports/ $filebase ".dft drc"]
redirect $filename { dft_drc -verbose -coverage_estimate }
# report scan path
set filename [format "%s%s%s" ./reports/ $filebase ".scan path"]
redirect $filename { report_scan_path -view existing -chain all }
# report cells
set filename [format "%s%s%s" ./reports/ $filebase ".cell"]
redirect $filename { report_cell }
# Write out protocol
set filename [format "%s%s%s" ./src/ $filebase ".spf"]
write test protocol -output $filename
# Write out scan chain design
set filename [format "%s%s%s" ./src/ $filebase ".v"]
```

```
redirect change names { change names -rules verilog -hierarchy -verbose }
write -format verilog -hierarchy -output $filename
#####################################
# this is the timing constraints file generated from the
# conditions above - used in the place and route program
set filename [format "%s%s%s" ./src/ $filebase ".sdc"]
write sdc $filename
####################################
# quit dc
if { $exit dc == 1} {
exit
tmax atpg.tcl:
#### TetraMax Script for ECE 4150/6250
#### Performs ATPG Pattern Generation for Synopsys Generic files
#### note: this script will only run in TMAX TCL mode
#### start tmax like this: tmax -tcl
#### local variables, designer must change these values ####
************************
set top module ripplecarry4 clk
set synthesized files [list ./src/ripplecarry4 clk scan.v]
set cell_lib ./src/osu05_stdcells.v set
scan_lib ./src/osu_scan.v
set stil file [list ./src/ripplecarry4_clk_scan.spf]
#### read in standard cells and user's design ###
# remove any other designs from design compiler's memory read netlist
-delete
# read in standard cell library read netlist
$cell lib -library
# read in scan cell library read netlist
$scan lib -library
# read in user's synthesized verilog code read netlist
$synthesized files
run build model $top module #
ignoring warnings like N20 or B10
```

```
# Set STIL file from DFT Compiler set_drc
$stil file
# run check to see if synthesized code violates any testing rules run drc
#### Generate ATPG (patterns) - full sequential
# capture all faults, 9 capture cycles
set atpg -capture cycles 9 -full seg atpg
remove faults -all add faults -all
# run atpg in full sequential mode run atpg
full sequential only
# write out patterns (overwrite old files)
write patterns ./src/${top module} tb patterns.v -replace -internal -format verilog single file
parallel 0
#### Output reports
report_patterns -all >> ./reports/${top_module}.tmax.patterns
report violations -all >> ./reports/${top module}.tmax.violations
report faults -summary -collapsed >> ./reports/${top_module}.tmax.coverage
#### Analyze Faults
# up to user to run these commands, they can inspect the faults and various reasons for them:
#analyze faults -class an
#analyze_faults -class an -verbose -max 3
#analyze faults in a reg reg/p dregscan0/q -stuck 1
ripplecarry4 clk.v:
module ripplecarry4 clk (sum, cout, a, b, cin, clk, rst);
input [3:0] a, b; input cin, clk, rst; output
[3:0] sum ; output cout ;
   wire wire0, wire1, wire2;
reg c0 reg, c1 reg, c2 reg;
fulladder fa0( .s(sum[0]), .cout(wire0), .a(a[0]), .b(b[0]), .cin(cin)
full adder \ fal(\ .s(sum[1]),\ .cout(wirel),\ .a(a[1]),\ .b(b[1]),\ .cin(c0\_reg)\ );
fulladder fa2( .s(sum[2]), .cout(wire2), .a(a[2]), .b(b[2]), .cin(c1_reg) );
fulladder fa3( .s(sum[3]), .cout(cout), .a(a[3]), .b(b[3]), .cin(c2_reg) );
always @(posedge clk)
                     begin
      if(rst)
      begin
             c0_reg <= 0 ;
             c1 reg <= 0 ;
             c2 reg <= 0 ;
             end
             else
                    begin
                    c0 reg <= wire0 ;
                    c1 reg <= wire1 ;
                    c2 reg <= wire2 ;
                                      end
             end
```